

## ZXMN2B01F 20V SOT23 N-channel enhancement mode MOSFET with low gate drive capability

### Summary

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)
	0.100 @ V <sub>GS</sub> = 4.5V	2.4
20	0.150 @ V <sub>GS</sub> = 2.5V	2.0
	0.200 @ V <sub>GS</sub> = 1.8V	1.7



This new generation trench MOSFET from Zetex features low onresistance achievable with low gate drive.

### Features

- Low on-resistance
- · Fast switching speed
- · Low gate drive capability
- SOT23 package

### Applications

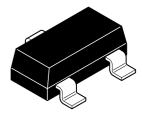
- DC-DC converters
- Power management functions
- Disconnect switches
- Motor control

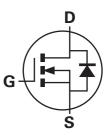
### Ordering information

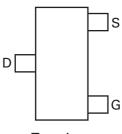
Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2B01FTA	7	8	3,000

### **Device marking**

2B1









## Absolute maximum ratings

Parameter	Symbol	Limit	Unit	
Drain-source voltage	V <sub>DSS</sub>	20	V	
Gate-source voltage	V <sub>GS</sub>	±8	V	
Continuous drain current	@ $V_{GS}$ = 4.5V; $T_{amb}$ =25°C <sup>(b)</sup>	Ι <sub>D</sub>	2.4	А
	@ $V_{GS}$ = 4.5V; $T_{amb}$ =70°C <sup>(b)</sup>		1.9	А
	@ $V_{GS}$ = 4.5V; $T_{amb}$ =25°C <sup>(a)</sup>		2.1	А
Pulsed drain current <sup>(c)</sup>	I <sub>DM</sub>	11.8	А	
Continuous source current	۱ <sub>S</sub>	1.4	А	
Pulsed source current (boo	I <sub>SM</sub>	11.8	А	
Power dissipation at T <sub>amb</sub> :	PD	625	mW	
Linear derating factor		5	mW/°C	
Power dissipation at T <sub>amb</sub> :	PD	806	mW	
Linear derating factor		6.4	mW/°C	
Operating and storage tem	T <sub>j</sub> , T <sub>stg</sub>	-55 to +150	°C	

### Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient <sup>(a)</sup>	$R_{\ThetaJA}$	200	°C/W
Junction to ambient <sup>(b)</sup>	$R_{\ThetaJA}$	155	°C/W

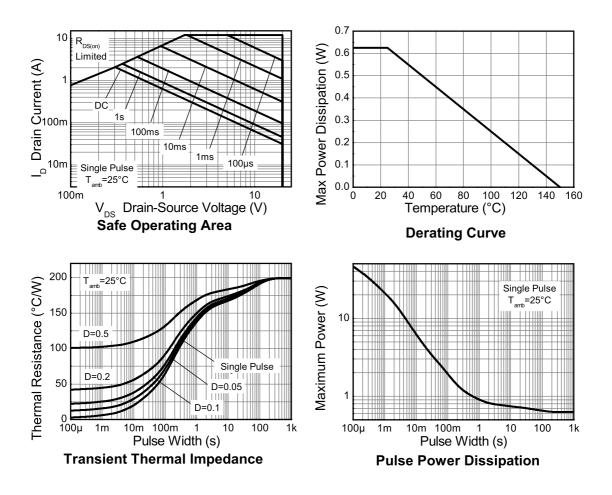
### NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t  ${\leq}5$  sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300µs - pulse width limited by maximum junction temperature.

### **Thermal characteristics**



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	20			V	I <sub>D</sub> = 250μA, V <sub>GS</sub> =0V
Zero gate voltage drain current	I <sub>DSS</sub>			1	μA	V <sub>DS</sub> = 20V, V <sub>GS</sub> =0V
Gate-body leakage	I <sub>GSS</sub>			100	nA	$V_{GS}=\pm 8V, V_{DS}=0V$
Gate-source threshold voltage	V <sub>GS(th)</sub>	0.4		1.0	V	$I_D = 250 \mu A$ , $V_{DS} = V_{GS}$
Static drain-source on-state	R <sub>DS(on)</sub>			0.100	Ω	$V_{GS}$ = 4.5V, I <sub>D</sub> = 2.4A
resistance <sup>(*)</sup>				0.150	Ω	$V_{GS}$ = 2.5V, I <sub>D</sub> = 2.0A
				0.200	Ω	V <sub>GS</sub> = 1.8V, I <sub>D</sub> = 1.7A
Forward transconductance <sup>(*)(‡)</sup>	9 <sub>fs</sub>		6.1		S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 2.4A
Dynamic <sup>(‡)</sup>	•					
Input capacitance	C <sub>iss</sub>		370		pF	V <sub>DS</sub> = 10V, V <sub>GS</sub> =0V
Output capacitance	C <sub>oss</sub>		81		pF	f=1MHz
Reverse transfer capacitance	C <sub>rss</sub>		46		pF	
Switching <sup>(†)</sup> <sup>(‡)</sup>			•			
Turn-on-delay time	t <sub>d(on)</sub>		2.2		ns	V <sub>DD</sub> = 10V, V <sub>GS</sub> = 4.5V
Rise time	t <sub>r</sub>		3.6		ns	I <sub>D</sub> = 1A
Turn-off delay time	t <sub>d(off)</sub>		17.8		ns	$R_{G} \approx 6.0\Omega$
Fall time	t <sub>f</sub>		10.5		ns	
Total gate charge	Qg		4.8		nC	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 4.5V
Gate-source charge	Q <sub>gs</sub>		0.6		nC	I <sub>D</sub> = 2.4A
Gate drain charge	0 <sub>gd</sub>		1.0		nC	
Source-drain diode	•					
Diode forward voltage <sup>(*)</sup>	V <sub>SD</sub>		0.73	0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> = 1.2A, V <sub>GS</sub> =0V
Reverse recovery time <sup>(‡)</sup>	t <sub>rr</sub>		6.7		ns	T <sub>j</sub> =25°C, I <sub>F</sub> = 1.1A,
Reverse recovery charge <sup>(‡)</sup>	0 <sub>rr</sub>		1.3		nC	di/dt=100A/ms

## Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

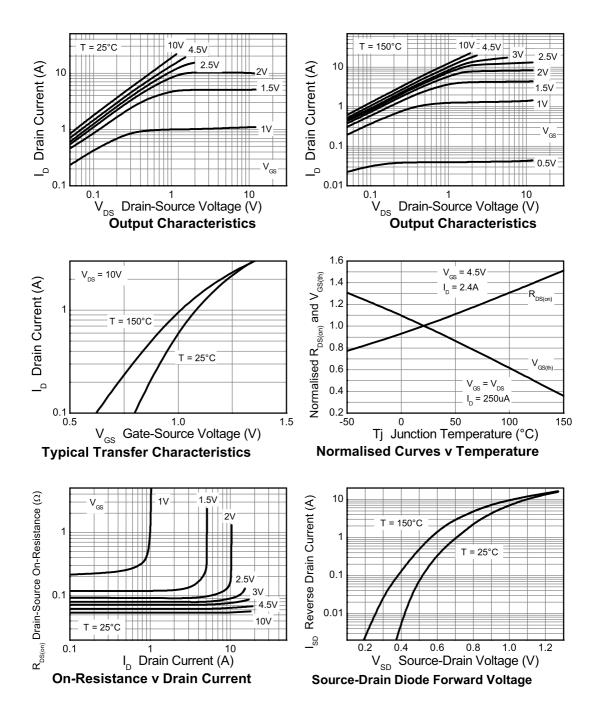
### NOTES:

(\*) Measured under pulsed conditions. Pulse width  $\leq$  300 $\mu$ s; duty cycle  $\leq$  2%.

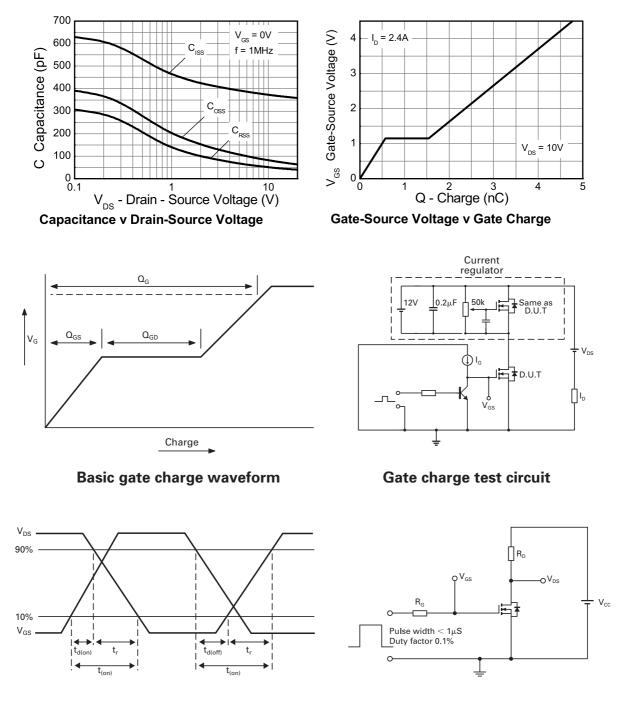
(†) Switching characteristics are independent of operating junction temperature.

(‡) For design aid only, not subject to production testing.

### **Typical characteristics**



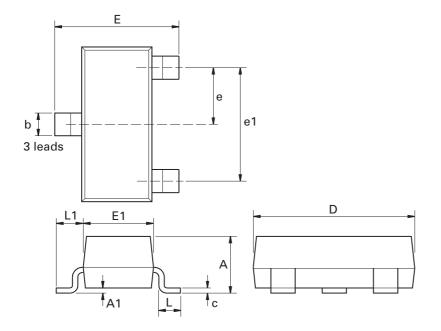
## **Typical characteristics**



Switching time test circuit

Switching time waveforms

## Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Dim. Millime		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
А	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	E	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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